



United States Patent and Trademark Office

IEEE Xplore®  
1 Million Documents  
1 Million Users

Help   FAQ   Terms   IEEE   Quick Links   

Peer Review

Search Results

## Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents


- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

## Member Services

- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 Print Format

## Full-text Search Prototype Results

[Feedback](#) [Help](#)

Your search matched **10** of **16** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

## Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

  
☐ Check to search within this result set

## Results Key:

**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

1 **A 400-MHz S/390 microprocessor**

Webb, C.F.; Anderson, C.J.; Sigal, L.; Shepard, K.L.; Liptay, J.S.; Warnock, J.D.; Curran, B.; Krumm, B.W.; Mayo, M.D.; Camporese, P.J.; Schwarz, E.M.; Farrell, M.S.; Restle, P.J.; Averill, R.M., III; Slegel, T.J.; Houtt, W.V.; Chan, Y.H.; Wile, B.; Nguyen, T.N.; Emma, P.G.; Beece, D.K.; Ching-Te Chuang; Price, C.; Solid-State Circuits, IEEE Journal of, Volume: 32, Issue: 11, Nov. 1997  
Pages:1665 - 1675

[\[Abstract\]](#)   [\[PDF Full-Text \(224 KB\)\]](#)   **IEEE JNL**

2 **Upset-like fault injection in VHDL descriptions: A method and preliminary results**

Velazco, R.; Leveugle, R.; Calvo, O.; Defect and Fault Tolerance in VLSI Systems, 2001. Proceedings. 2001 IEEE International Symposium on, 24-26 Oct. 2001  
Pages:259 - 267

[\[Abstract\]](#)   [\[PDF Full-Text \(170 KB\)\]](#)   **IEEE CNF**

3 **A Study of Random Channel Errors for an ADM System**

Prezas, D.; LoCicero, J.; Communications, IEEE Transactions on [legacy, pre - 1988], Volume: 29, Issue: 2, Feb 1981  
Pages:117 - 122

[\[Abstract\]](#)   [\[PDF Full-Text \(512 KB\)\]](#)   **IEEE JNL**

**4 A programmable gate array based integrated circuit for high bit rate telecommunications transmission system applications**

*Mallett, C.T.; Tomkins, J.W.; Nagra, A.S.T.;*

Solid-State Circuits, IEEE Journal of , Volume: 17 , Issue: 3 , Jun 1982

Pages:586 - 588

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) IEEE JNL

---

**5 New Products**

Communications Magazine, IEEE , Volume: 20 , Issue: 5 , Sep 1982

Pages:43 - 45

[\[Abstract\]](#) [\[PDF Full-Text \(456 KB\)\]](#) IEEE JNL

---

**6 New products**

Communications Magazine, IEEE , Volume: 24 , Issue: 4 , Apr 1986

Pages:50 - 51

[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) IEEE JNL

---

**7 A Compact 4-GHz Linearize for Space Use**

*Inada, R.; Ogawa, H.; Kitazume, S.; Desantis, P.;*

Microwave Theory and Techniques, IEEE Transactions on , Volume: 34 , Issue: 12 , Dec 1986

Pages:1327 - 1332

[\[Abstract\]](#) [\[PDF Full-Text \(528 KB\)\]](#) IEEE JNL

---

**8 ErrorTracer: design error diagnosis based on fault simulation techniques**

*Shi-Yu Huang; Kwang-Ting Cheng;*

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 18 , Issue: 9 , Sept. 1999

Pages:1341 - 1352

[\[Abstract\]](#) [\[PDF Full-Text \(256 KB\)\]](#) IEEE JNL

---

**9 REMOD: a new methodology for designing fault-tolerant arithmetic circuits**

*Dutt, S.; Hanchek, F.;*

Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume: 5 , Issue: 1 , March 1997

Pages:34 - 56

[\[Abstract\]](#) [\[PDF Full-Text \(812 KB\)\]](#) IEEE JNL

---

**10 Framework for testing the fault-tolerance of systems including OS and network aspects**

*Buchacker, K.; Sieh, V.;*

High Assurance Systems Engineering, 2001. Sixth IEEE

International Symposium on , 22-24 Oct. 2001

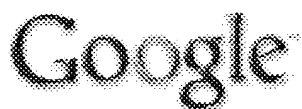
Pages:95 - 105

[\[Abstract\]](#)   [\[PDF Full-Text \(164 KB\)\]](#)   **IEEE CNF**

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#)  
| [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE](#)  
[Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#)<sup>New!</sup> [more »](#)

error test "Fault Apply register"

Search

[Advanced Search](#)  
[Preferences](#)

## Web

Tip: Try removing quotes from your search to get more results.

Your search - **error test "Fault Apply register"** - did not match any documents.

### Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

Also, you can try [Google Answers](#) for expert help with your search.

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2004 Google

### Sponsored Links

[Application Error? Fix It](#)  
Distributor of Free Download Tools.  
Auto-Fix Any Application **Error** Fast  
[FreeDownloadtools.com/](#)

[See your message here...](#)